# Abstracts

## W-Band Noise Figure Measurement Designed for On-Wafer Characterisation

*R. Drury, R.D. Pollard and C.M. Snowden. "W-Band Noise Figure Measurement Designed for On-Wafer Characterisation." 1996 MTT-S International Microwave Symposium Digest 96.3 (1996 Vol. III [MWSYM]): 1273-1276.*

The first fully automated noise and S-parameter measurement bench is reported for W-band on-wafer characterisation. A calibration procedure is described that allows the receiver reference plane to be accurately moved to the probe tip.

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